

<b>Notice of References Cited</b>	Application/Control No. 10/656,534	Applicant(s)/Patent Under Reexamination BANG ET AL.	
	Examiner Alexander O. Williams	Art Unit 2826	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,137,164	10-2000	Yew et al.	257/686
	B	US-6,437,990 B1	08-2002	Degani et al.	361/783
	C	US-6,734,539 B2	05-2004	Degani et al.	257/686
	D	US-2002/0081755 A1	06-2002	Degani et al.	438/14
	E	US-6,376,917 B1	04-2002	Takeshita et al.	257/778
	F	US-6,680,212 B2	01-2004	Degani et al.	438/14
	G	US-2004/0021210 A1	02-2004	Hosomi, Eiichi	257/686
	H	US-2003/0110452 A1	06-2003	Leahy et al.	716/1
	I	US-2002/0079568 A1	06-2002	Degani et al.	257/686
	J	US-2001/0046129 A1	11-2001	Broglia et al.	361/803
	K	US-2002/0127771 A1	09-2002	Akram et al.	438/107
	L	US-2004/0178508 A1	09-2004	Nishimura et al.	257/778
	M	US-6,765,288 B2	07-2004	Damberg, Philip	257/698

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.